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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/840,386	04/23/2001	Yoshihisa Matsubara	NEKA 18.612 2510		
26304	7590 09/16/2004		EXAMINER		
KATTEN MUCHIN ZAVIS ROSENMAN 575 MADISON AVENUE			VINH, LAN		
	NEW YORK, NY 10022-2585			PAPER NUMBER	
			1765		

DATE MAILED: 09/16/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
	09/840,386	MATSUBARA ET AL.			
Office Action Summary	Examiner	Art Unit			
	Lan Vinh	1765			
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). - Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b). Status					
1)⊠ Responsive to communication(s) filed on 20 July 2004 .					
	nis action is non-final.				
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213. Disposition of Claims					
4)⊠ Claim(s) <u>1,2 and 4-11</u> is/are pending in the application.					
4a) Of the above claim(s) <u>4-11</u> is/are withdrawn from consideration.					
5) Claim(s) is/are allowed.					
6)⊠ Claim(s) <u>1 and 2</u> is/are rejected.					
7) Claim(s) is/are objected to.					
8) Claim(s) are subject to restriction and/or election requirement. Application Papers					
9)☐ The specification is objected to by the Examiner.					
10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.					
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
11) The proposed drawing correction filed on is: a) approved b) disapproved by the Examiner.					
	If approved, corrected drawings are required in reply to this Office action.				
12) The oath or declaration is objected to by the Examiner.					
Priority under 35 U.S.C. §§ 119 and 120					
13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).					
a)⊠ All b)□ Some * c)□ None of:					
1. Certified copies of the priority documents have been received.					
2. \boxtimes Certified copies of the priority documents have been received in Application No. <u>09/840386</u> .					
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
14) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).					
a) ☐ The translation of the foreign language provisional application has been received. 15) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.					
Attachment(s)					
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449) Paper No(s)	5) Notice of Informat	y (PTO-413) Paper No(s) Patent Application (PTO-152)			
U.S. Patent and Trademark Office PTO-326 (Rev. 04-01) Office Act	ion Summary	Part of Paper No. 091404			

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DETAILED ACTION

Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 7/20/2004 has been entered.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 3. Claim 1 is rejected under 35 U.S.C. 102(e) as being anticipated by Miyawaki et al (US 5,952,694).

Miyawaki discloses a method for manufacturing a semiconductor device. This method comprises the steps of:

forming N-type region and P-type region on a substrate (col 8, lines 63-64), forming electrode 30/wiring to connect the N and P-type region (col 9, lines 6-8; fig. 10)

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performing a cleaning step/processing step on the semiconductor substrate (col 20, lines 45-46), applying an etching solution/liquid to the semiconductor substrate to expose the wiring (col 20, lines 65-67, fig. 36), applying a He-Ne laser/light source on the upper surface of the semiconductor substrate (col 21, lines 32-34), the He-Se laser having a wavelength of 600 nm (col 8, lines 54-55), which overlaps the claimed range of 500 nm to less than 1 microns

Miyawaki also discloses performing the cleaning step after polishing the semiconductor substrate (col 13, lines 40-42)

Since the method of Miyawaki uses the same steps and a light source having the same wavelength as that of the claimed invention, then under the principle of inherency using the light source in the method of Miyawaki would inherently reduce an electromotive force at a PN junction in said semiconductor substrate, thereby inhibiting galvanic effect due to photo excitation before, during or after the step including CMP, and preventing oxidation of a surface of said wiring.

Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claim 2 is rejected under 35 U.S.C. 103(a) as being unpatentable over Miyawaki et al (US 5,952,694) in view of Klebanoff (US 6,169, 652)

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Miyawaki's method has been described above. Unlike the instant claimed invention as per claim 2, Miyawaki fails to disclose that the processing/cleaning step is performed in a state in which the semiconductor substrate is grounded.

However, Klebanoff, in a method of using different chucks to hold semiconductor wafer during processing, teaches maintaining/controlling the semiconductor substrate at zero voltage (ground potential) during processing (col 3, lines 15-17)

Since both Miyawaki and Klebanoff are concerned with the step of cleaning the semiconductor substrate, one skilled in the art would have found it obvious to modify Miyawaki method by maintaining/controlling the semiconductor substrate at zero voltage (ground potential) during processing as per Klebanoff because Klebanoff states that employing a voltage-controlled electrostatic chuck will significantly reduce the likelihood of contaminant deposition on the substrate (see abstract).

Response to Arguments

6. Applicant's arguments with respect to claims 1-2 have been considered but are moot in view of the new ground(s) of rejection.

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Conclusion

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7. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Lan Vinh whose telephone number is 571 272 1471. The examiner can normally be reached on M-F 8:30-5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nadine Norton can be reached on 571 272 1465. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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September 15, 2004